25<sup>th</sup>-26<sup>th</sup> June 2019 University of Huddersfield



#### **CONFERENCE SCHEDULE**

Day one: Tuesday 25 <sup>th</sup> June 2019		
9.00	Registration and refreshments	
9.30	Introduction and Welcome talk	
9.45	Keynote Presentation Markus Bartscher, PTB: Path to Traceable Dimensional CT	
10.15	Nathanael Turner, MTC: Study on Methods to Increase Voxel Resolution	
10.30	Peter Westenberger, Thermo Fisher Scientific: Automated Industrial inspection incorporating acquisition errors	
10.45	Tristan Lowe, University of Manchester: <i>Defining spatial resolution in X-ray Computed Tomography for industrial applications</i>	
11.00	Break and refreshments	
11.30	Keynote Presentation Johann Henckel, University College London: Medical & Micro CT aids the understanding of wear in Orthopaedic Implants	
12.00	Patrick Zippert, University Friedrich-Alexander Erlangen-Nurnberg: An analysis of dimensional accuracy of clinical CT systems	
12.15	Matthew Holland, University of Huddersfield: <i>Use of Micro-CT for the measurement of wear in UHMWPE Total Ankle Replacement components</i>	
12.30	Lunch	
13.30	Keynote Presentation Desi Bacheva, Hieta Technologies: Challenges in inspecting additive manufactured heat exchangers	
14.00	Mason Rowbottom, TWI: <b>Generation of a calibration artefact for the</b> setting of optimal XCT parameters for measurement of porosity in SLM components	

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Fernando Ferreira, CATIM: <i>Influence of voxel size on CT measurements of form errors in additive manufactured parts</i>
Adam Thompson, University of Nottingham: <i>X-ray computed tomography surface topography measurement: industrial case studies</i>
Valdis Krumins, AMRC: Correcting CAD models for SLM build defects
Break and refreshments
David Bate, Nikon Metrology: 3in1 project: Surface roughness on AM parts integrated with other NDT processes
Alan Wilson, NPL: <b>Dimensional XCT measurement: the effects of form error</b> and surface roughness on the magnitude of extracted characteristics
Stephen Cullen, TWI: Laser Metal Deposition, Laser Power Analysis and Optimisation through the use of XCT
Tukun Li, University of Huddersfield: WINGS+ Project Introduction
Drinks Reception
Carriages for Conference Dinner at Yorkshire Sculpture Park
Tours at Yorkshire Sculpture Park
Conference Dinner

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Day two: Wednesday 26 <sup>th</sup> June 2019		
8.45	Coffee	
9.15	Keynote Presentation Wenjuan Sun, NPL: Quantitative evaluation using fast XCT for industrial applications	
9.45	Rabia Ince, Diamond Light Source: <b>Dynamic Metrology Measurements of XCT Sample Stage</b>	
10.00	Miran Park, KAIST: A novel and fast X-ray in-line defect inspection technique for ball grid array structures in 3D packaging	
10.15	Osman Ajmal, NPL: <i>Thresholding Determination in multi-material evaluation</i>	
10.30	Younes Chahid, University of Huddersfield: <i>Ranking of XCT setting</i> combinations for dimensional metrology using 2D image analysis prior to reconstruction	
10.45	Refreshment break and Poster Session	
11.30	Ander Biguri, Mu-Vis Southampton: <i>Multi-GPU TIGRE: Very large image</i> reconstruction using iterative algorithms	
11.45	Arturo Mendoza, Safran: Beam hardening for composite materials	
12.00	Shada Kazemi, NPL: Characterisation of scattering effect in X-Ray computed tomography	
12.15	Xuekun Lu, University College London: <i>The correlation of 3D microstructure</i> and performance in Energy Storage Devices using Multi length Scale XCT	
12.30	Gerd Schwaderer, Volume Graphics: Foam structure analysis and powder characterisation	
12.45	Introduction to DXCT 2020: Martin Turner and Tristan Lowe	
13.00	Prize Giving and Lunch	
14.00	Discussion session - BSI Standardisation Update	
15.00	Conference Close	

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## Wednesday 26th June 2019

#### **Poster Session**

Emil Espes, Excillum: X-ray sources for high throughput and extreme resolutions

Yushan Gao, University of Southampton: *A parallel stochastic algorithm for large scale CT reconstruction* 

Xiuyuan Yang, Cranfield University: **Evaluation of scattering effects in X-ray computed tomography for dimensional metrology** 

Christopher Thornton, STFC: Next generation laser-based X-ray sources for computed tomography

Jian Qiu, NPL: A preliminary study on noise reduction methods in industrial XCT

Nadia Kourra, WMG: Industrial image processing method for additive manufacturing specimens for removing supporting material for visual and metrological investigations

Reuben Lindroos, University of Southampton: *The FISTA algorithm for CT reconstruction in dimensional metrology* 

Lars Korner, University of Nottingham: **Simulation of continuous high aspect ratio tomography for surface topography measurements**